

FORM PTO-1449  
(REV. 7-80)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

5005.1109

APPLICATION NO.

To be assigned

**LIST OF PRIOR ART CITED BY APPLICANT**

(Use several sheets if necessary)

APPLICANT

Hilmar GUGEL

FILING DATE 3/3/06

Herewith

GROUP 2872

To be assigned

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
/ACL/	A01	6,667,830	Dec. 23, 2003	Iketaki et al.	359	368	
/ACL/	A02	2002/0167724	Nov. 14, 2002	Iketaki et al.	359	385	
/ACL/	A03	5,731,588	Mar. 24, 1998	Hell et al.	250	458.1	
/ACL/	A04	3,437,395	Apr. 8, 1969	H.E. Rosenberger et al.	350	9	
/ACL/	A05	2002/0109913	Aug. 15, 2002	Gugel et al.	359	387	
/ACL/	A06	6,555,826	Apr. 29, 2003	Hoffmann	250	458.1	
	A07						
	A08						
	A09						
	A10						

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	NO
							YES	
/ACL/	A11	DE 44 16 558	Aug. 3, 1995	DE-Germany			Corresponds to US 5,731,588	
/ACL/	A12	DE 100 12 462	Sep. 20, 2001	DE-Germany			Corresponds to US 6,555,826	
/ACL/	A13	EP 0 491 289	Jun. 24, 1992	EP-Europe			Discussed in paragraph 10 of specification; see abstract	
	A14							

**OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)**

/ACL/	A15	Int. Search Report for Int. Application Serial No. PCT/EP2004/051877 (3 pages) November 2004						
/ACL/	A16	M. DYBA et al.: "Focal Spots of Size Lambda/23 Open Far-Field Fluorescence Microscopy at 33nm Axial Resolution", Physical Review Letters, Vol. 88, No. 16, Apr. 22, 2002, pp. 163901-1-163901-4						
/ACL/	A17	T.A. KLAR et al.: Breaking Abbe's Diffraction Resolution Limit in Fluorescence Microscopy with Stimulated Emission Depletion Beams of Various Shapes", Physical Review E, Vol. 64, No. 066613, Nov. 26, 2001, pp. 066613-1-066613-9						
/ACL/	A18	V. Westphal et al.: "Laser-Diode-Stimulated Emission Depletion Microscopy", Applied Physics Letters, Vol. 82, No. 18, 5 May 2003, pp. 3125-3127						
/ACL/	A19	T.A. Klar et al.: "Fluorescence Microscopy with Diffraction Resolution Barrier Broken by Stimulated Emission", Proc. Natl. Acad. Sci. U.S.A., Vol. 97, No. 15, 18 July 2000, pp. 8206-8210						
	A20							

EXAMINER /Arnel C. Lavarias/

DATE CONSIDERED 06/30/2008

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.